

Notice of References Cited	Application/Control No. 10/019,052	Applicant(s)/Patent Under Reexamination NEW ET AL.	
	Examiner Mark L. Shibuya	Art Unit 1639	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0095962	05-2003	Ueda et al.	424/130.1
*	B	US-5,851,536	12-1998	Yager et al.	424/400
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 95/02684 A1	01-1995	WIPO	CRABTREE et al.	C12N 5/00
	O	WO 96/23881 A1	08-1996	WIPO	CAPON et al.	C12N 15/12
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.